Privacy and Security for IoT Devices

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Deadline for manuscript submissions:
closed (15 March 2024)

Message from the Guest Editors

To respond to this urgent call, in this Special Issue, we will discuss the possible attack surface of IoT devices by proposing the attacks with novel insights or performing measurement studies and case studies to understand the impacts of the attacks. We will propose novel detection methods, which can effectively identify a specific attack or a wide range of attacks against IoT devices. We will also propose and discuss the security protection of IoT devices. The Special Issue will present the state of the science for the most relevant problems in IoT security and privacy, and contribute to the IoT ecosystem in academic and industrial areas. We invite investigators to submit original research articles to this Special Issue.

Potential submission topics include but are not limited to the following:

- Attacks against security and privacy of IoT devices with novel insights;
- Case studies on attacks against IoT devices;
- Measurement studies on attacks against IoT devices with novel results;
- Detection methods for IoT device vulnerabilities;
- IoT protocol security;
- Security and privacy protection for IoT devices;
- Intrusion and anomaly detection for IoT devices.

Special Issue

Editor-in-Chief

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Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

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